Auger Microprobe Analysis

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Contents

Pro	Preface		
Acknowledgments			xi
1	Introduction and history		1
	1.1	Introduction	1
	1.2	History	4
2	The	Auger process	10
	2.1	Introduction	10
	2.2	Nomenclature related to the Auger process	13
	2.3	Theory of the Auger process	16
	2.4	Escape depths	25
	2.5	Dependence of Auger yield on exciting voltage	29
	2.6	Directional effects	32
	2.7	Magnetic effects	36
3	Seco	ondary emission	37
	3.1	Introduction	37
	3.2	The elastic peak	40
	3.3	Plasmon losses	42
	3.4	Ionization loss peaks	48
	3.5	Secondary electrons	50
	3.6	Insulating samples	52
4	The	role of chemistry in Auger analysis	55
	4.1	Introduction	55
	4.2	Chemical effects in Auger analysis	55
	4.3	Interatomic transitions	86
	4.4	Auger behaviour of the lightest ($Z \leq 3$) elements	90
	4.5	Beam effects	92

•	~
V1	Contents

5	The	methods of Auger analysis	100
	5.1	Introduction	100
	5.2	Qualitative Auger analysis	101
	5.3	Quantification of Auger data from a homogeneous solid	102
	5.4	Ouantification of Auger data from surface layers	114
	5.5	Depth profiling (sputtering)	118
6	Vac	18	140
	6.1	Units of measurement	140
	6.2	Introduction	141
	6.3	Useful relationships	142
	6.4	Useful concepts	145
	6.5	Outgassing	148
	6.6	Problems of operating in ultrahigh vacuum	151
	6.7	Materials for use in ultrahigh vacuum	155
	6.8	Pumps	159
	6.9	Vacuum gauges	166
	6.10	Mass spectrometers (gas analysers)	171
	6.11	Residual gases	173
	6.12	Leaks	174
	6.13	Components of an ultrahigh vacuum system	180
	6.14	General rules for operating a vacuum system	187
			101
	Aug	er signal detection	191
	7.1	Introduction	191
	7.2	Electron spectrometers	191
	7.3	Methods of signal detection	210
,	7.4	Modulation techniques	212
	7.5 7.6	Spin-polarized electrons	225 228
8	Scan	ning electron microscopy	231
	8.1	General	231
	8.2	Signal detection in a scanning electron microscope	233
	8.3	The electron optical column	236
9	The	Auger microprobe: general principles	946
5	91	Introductory review	946
	99	Practical possibilities: the Auger microprobe	240 947
	93	Practical possibilities: the Auger man	217 955
	94	Snatial resolution	255
	9.5	The problem of topography	237 973
	0.0	The prostent of topography	215

L

V

1	0 The	Auger microprobe: the developing instrument	276
	10.1	Introduction	276
	10.2	The scanning-electron-microscope-based Auger	
		microprobe	276
	10.3	Scanning-electron-microscope-based Auger micro-	
		probes with field emission tips	282
	10.4	Introduction to commercial scanning-electron-	
		microscope-based Auger microprobes	284
	10.5	Commercial scanning-electron-microscope-based	
		Auger microprobes	284
	10.6	Introduction to commercial cylindrical-mirror-	
		analyser-based Auger microprobes	289
	10.7	Commercial cylindrical-mirror-analyser-based Auger	
		microprobes	289
	10.8	Auger microprobes based upon concentric	
		hemispherical analysers	293
	10.9	Automated (computerized) Auger microprobes	295
	10.10	Multi-technique systems involving Auger microprobe	
		analysis	299
1	1 The A	Auger microprobe: techniques	307
	11.1	The Auger laboratory	307
	11.2	Auger sample preparation and mounting	312
	11.3	Sample movement	315
	11.4	Integral specimen preparation 'devices' and chambers	315
	11.5	Specimen transfer	316
	11.6	Subsurface Auger analysis	317
	11.7	The analysis of cross sections	318
	11.8	The analysis of insulators	318
	11.9	The analysis of radioactive materials	320
	11.10	Replication	320
	11.11	Problems in interrelating measurements	321
1	2 The A	Auger microprobe: applications	324
	12.1	Introduction	324
	12.2	Microcircuitry	325
	12.3	Materials failure	327
	12.4	Corrosion	330
	12.5	Tribology	332
	12.6	Nuclear applications	333
	12.7	Electrical industry	334
	12.8	Environmental sampling	335
	12.9	Catalysts	336
	12.10	Miscellaneous	336
	12.11	'Basic' studies	338

Contents

Station

13	Other surface-analytical techniques and epilogue		
	(MICROESCA)	341	
	13.1 General	341	
	13.2 Electron-based techniques	341	
	13.3 Photon-based techniques	342	
	13.4 Ion-based techniques	343	
	13.5 Micro electron spectroscopy for chemical analysis		
	(MICROESCA)	344	
Арр	endices		
1	Units and relationships	349	
2	Program for the calculation of the Auger yield		
3	Tables to correct for matrix effects in quantitative Auger		
	analysis		
4	Program to calculate desorption rates	364	
5	5 The abbreviations of the various methods used for		
	characterizing materials, together with the probe used	367	
6	Tables of Auger energies measured in derivative mode	376	
Ref	erences	383	
Ind	ex.	433	

viii